



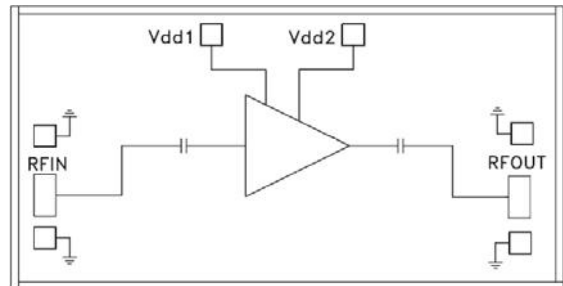
YTLA-1840E

GaAs MMIC Low Noise Amplifier Chip, 18-40GHz

Features:

- Frequency: 18-40GHz
- Small Signal Gain: 15dB
- Noise Figure: 3.0dB max.
- P-1dB: 5dBm
- Supplying: +5V/45mA
- 50Ohm Input/Output
- 100% Testing
- Chip Size: 2.25 x 1.6 x 0.09 mm

Functional Diagram:



General Description:

YTLA-1840E is a GaAs MMIC HEMT Self-biased, wideband Low Noise Amplifier Die Which operate between 18GHz~40GHz with small signal 15dB with noise figure 3.0dB. YTLA-1840E use +5V single supply.

Parameter ¹	
Max Drain Voltage	+7V
Max. input Power	+20dBm
Working Temperature	-55 ~ +85°C
Storage Temperature	-65 ~ +150°C

【1】 There is a risk of permanent damage over any of the above maximum limits .

Electrical Specifications($T_A = +25^\circ\text{C}$, $V_d = +5\text{V}$)				
Parameter	Min.	Type	Max	Units
Frequency	18-40			GHz
Small Signal Gain	13.5	15	17.5	dB
Flatness	±2.0			dB
Noise Figure	-	-	3.0	dB
P-1dB	-	5	-	dBm
Input Return Loss	15	18	-	dB
Output Return Loss	20	25	-	dB
Supply Current	45			mA

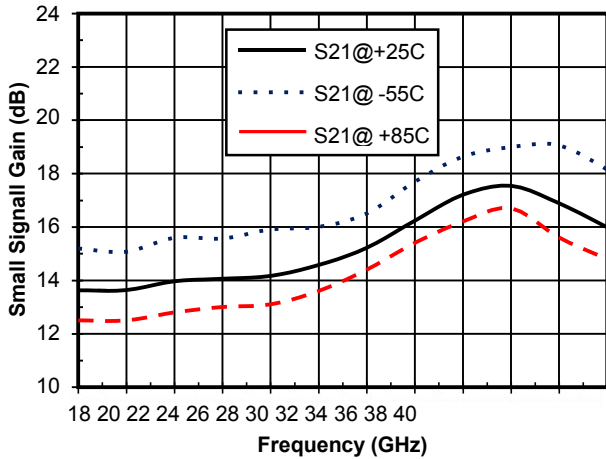


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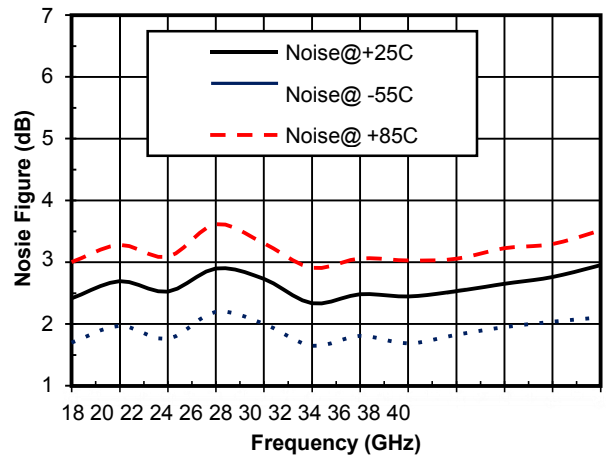
GaAs MMIC LNA Chip, 18-40GHz

Curve

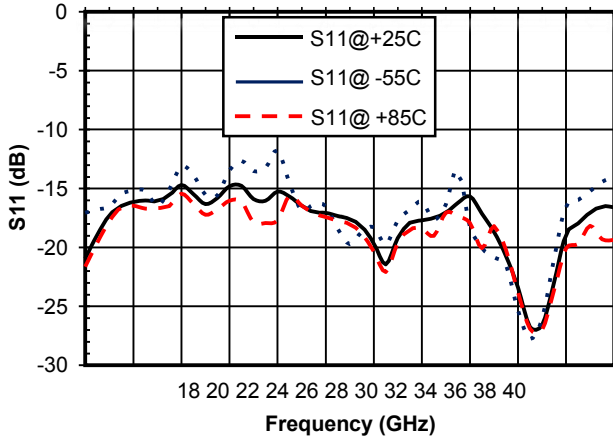
Gain vs. Frequency



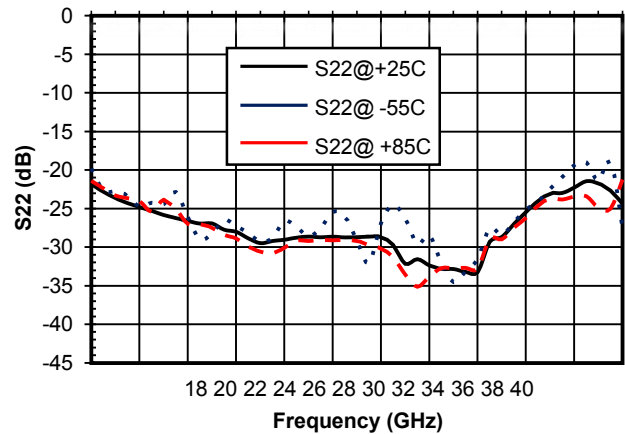
Noise Figure vs. Frequency



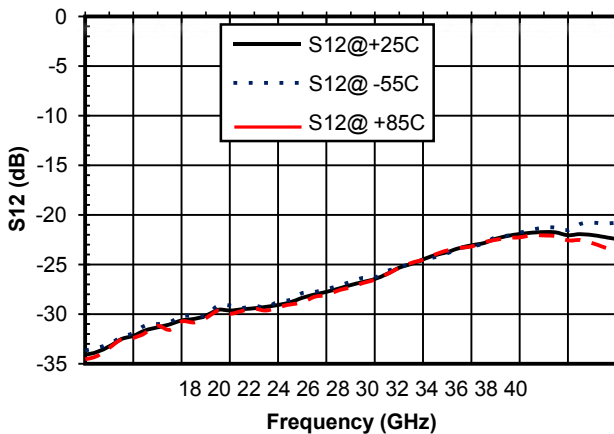
Input Return Loss vs. Frequency



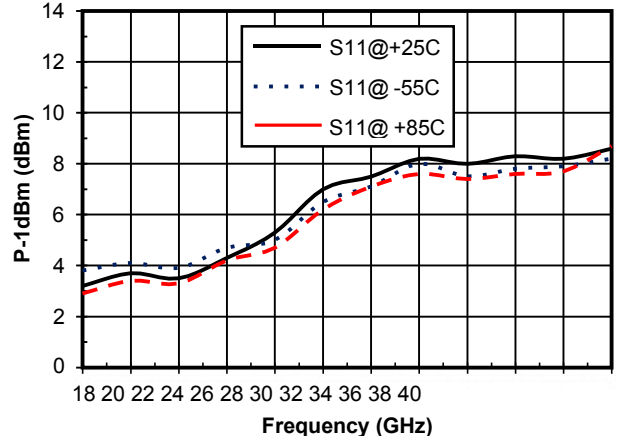
Output Return Loss vs. Frequency



Reverse Isolation vs. Frequency



P-1dB vs. Frequency

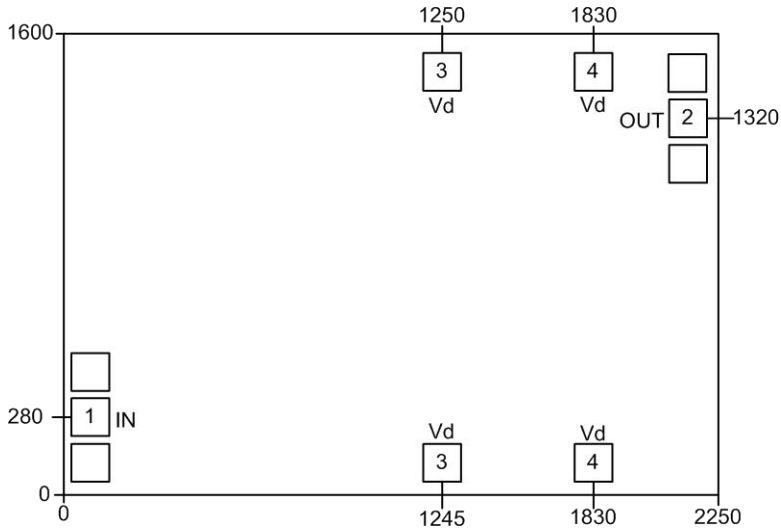




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Outline Drawing ²

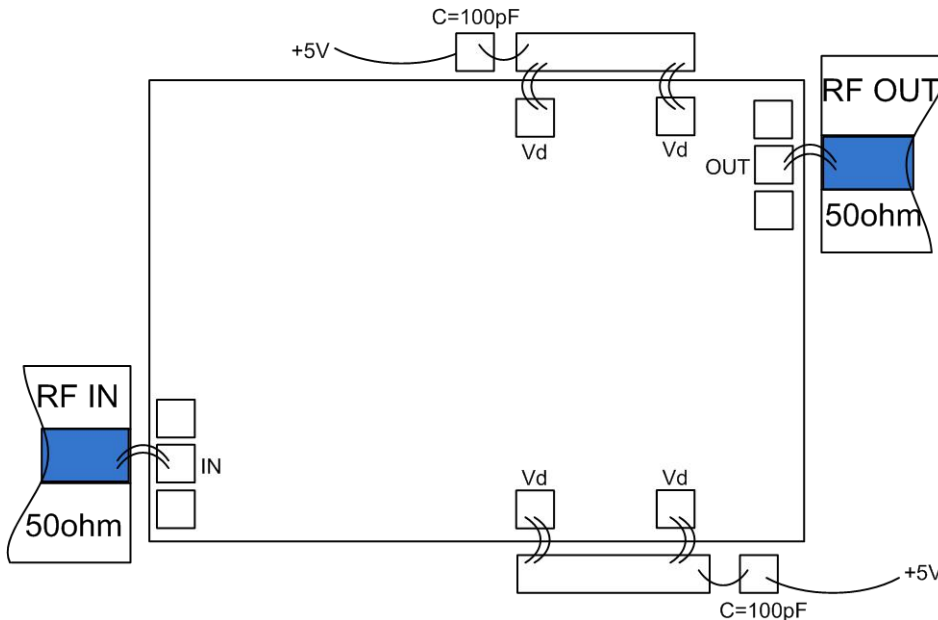


【2】 um

Pad Descriptions			
Part No.	Function	Description	Interface Schematic
1	RFIN	RF signal input, no straightening capacitor	
2	RFOUT	RF signal input, no straightening capacitor	
3	VD	Amplifier drain bias, external 100pf bypass capacitance, single side power supply, only one side of the bonding vd .	
Die Bottom	GND	Die bottom must be connected to RF/DC ground.	

GaAs MMIC LNA Chip, 18-40GHz

Assembly



【3】 single side power supply, only one side of the bonding vd .

Handling Precautions

- All bare die are placed in either Waffle or Gel based ESD protective containers, stored in a dry nitrogen environment.
 - Handle the chips in a clean environment. DO NOT attempt to clean the chip using liquid cleaning systems.
 - Follow ESD precautions to protect against ESD strikes.
 - Handle the chip along the edges with a vacuum collet or with a sharp pair of bent tweezers. The surface of the chip has fragile air bridges and should not be touched with vacuum collet, tweezers, or fingers.
 - The chip is back-metallized and can be die mounted with AuSn eutectic preforms or with electrically conductive epoxy. The mounting surface should be clean and flat.
 - temperature of 265 °C. When hot 90/10 nitrogen/hydrogen gas is applied, tool tip temperature should be 290 °C. DO NOT expose the chip to a temperature greater than 320 °C for more than 20 seconds. No more than 3 seconds of scrubbing should be required for attachment
 - Apply a minimum amount of epoxy to the mounting surface so that a thin epoxy fillet is observed around the perimeter of the chip once it is placed into position. Cure epoxy per the manufacturer's schedule.
- Ball bonds should be made with a force of 40-50 grams and wedge bonds at 18-22 grams. All bonds should be made with a nominal stage temperature of 150 °C. A minimum amount of ultrasonic energy should be applied to achieve reliable bonds.